

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant(s): T. HIROI, et al  
Serial No.: 10/062,666  
Filed: February 5, 2002  
For: PATTERN INSPECTION METHOD AND  
SYSTEM THEREFOR  
Group: 2881  
Examiner: J. Berman  
Conf. No.: 4688

**AMENDMENT**

Mail Stop: Amendment (Fee)  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

March 2, 2009

Sir:

The following amendments and remarks are respectfully submitted in connection with the above-identified application, in response to the office action dated September 9, 2008. The amendments submitted are as listed below and as set forth on the following pages:

Amendment of the Claims; and

Remarks are included following the amendments.